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Table of Contents

Message from General Co-chairs	xiv
Message from Technical Program Co-chairs	xv
Organizing Committee	xvi
Program Committee	xvii
Steering Committee	xix
Reviewers	xx

Session A1: Testing Clock and Timing

On Detecting Transition Faults in the Presence of Clock Delay Faults	1
<i>Yoshinobu Higami, Hiroshi Takahashi, Shin-ya Kobayashi, and Kewal K. Saluja</i>	
Testing of Clock-Domain Crossing Faults in Multi-core System-on-Chip	7
<i>Naghmeah Karimi, Zhiqiu Kong, Krishnendu Chakrabarty, Pallav Gupta, and Srinivas Patil</i>	
On-Chip Programmable Dual-Capture for Double Data Rate Interface Timing Test	15
<i>Hyunjin Kim and Jacob A. Abraham</i>	
Time Domain Characterization and Test of High Speed Signals Using Incoherent Sub-sampling	21
<i>Debesh Bhatta, Joshua W. Wells, and Abhijit Chatterjee</i>	

Session A2: Power Aware Testing I

Temperature Dependent Test Scheduling for Multi-core System-on-Chip	27
<i>Chunhua Yao, Kewal K. Saluja, and Parameswaran Ramanathan</i>	
Test Scheduling for Multicore SoCs with Dynamic Voltage Scaling and Multiple Voltage Islands	33
<i>Xrysovalantis Kavousianos, Krishnendu Chakrabarty, Arvind Jain, and Rubin Parekhji</i>	
Selective Test Response Collection for Low-Power Scan Testing with Well-Compressed Test Data	40
<i>Dong Xiang and Zhen Chen</i>	

Low Power Test-Compression for High Test-Quality and Low Test-Data	
Volume	46
<i>Vasileios Tenentes and Xrysovalantis Kavousianos</i>	

Session A3: Advanced Design for Testability Techniques

Multi-cycle Test with Partial Observation on Scan-Based BIST Structure	54
<i>Yasuo Sato, Hisato Yamaguchi, Makoto Matsuzono, and Seiji Kajihara</i>	
SSTKR: Secure and Testable Scan Design through Test Key Randomization	60
<i>Mohammed Abdul Razzaq, Virendra Singh, and Adit Singh</i>	
An Innovative Methodology for Scan Chain Insertion and Analysis at RTL	66
<i>Lilia Zaourar, Yann Kieffer, and Chouki Aktouf</i>	
Adaptation of Standard RT Level BIST Architectures for System Level	
Communication Testing	72
<i>Nastaran Nematì and Zainalabedin Navabi</i>	

Session A4: Power Aware Testing II

Rewind-Support for Peak Capture Power Reduction in Launch-Off-Shift	
Testing	78
<i>Ozgur Sinanoglu</i>	
Low Power Decompressor and PRPG with Constant Value Broadcast	84
<i>Michal Filipek, Yoshiaki Fukui, Hiroyuki Iwata, Grzegorz Mrugalski,</i> <i>Janusz Rajski, Masahiro Takakura, and Jerzy Tyszer</i>	
Effective Launch-to-Capture Power Reduction for LOS Scheme	
with Adjacent-Probability-Based X-Filling	90
<i>K. Miyase, Y. Uchinodan, K. Enokimoto, Y. Yamato, X. Wen, S. Kajihara,</i> <i>F. Wu, L. Dilillo, A. Bosio, P. Girard, and A. Virazel</i>	
Virtual Circuit Model for Low Power Scan Testing in Linear	
Decompressor-Based Compression Environment	96
<i>Zhen Chen, Jia Li, Dong Xiang, and Yu Huang</i>	

Session A5: Defect Based Test Techniques

Test Pattern Selection for Defect-Aware Test	102
<i>Yoshinobu Higami, Hiroshi Furutani, Takao Sakai, Shuichi Kameyama,</i> <i>and Hiroshi Takahashi</i>	
Efficient SAT-Based Search for Longest Sensitisable Paths	108
<i>Matthias Sauer, Jie Jiang, Alexander Czutro, Ilia Polian, and Bernd Becker</i>	

Mapping Transaction Level Faults to Stuck-At Faults in Communication Hardware	114
<i>Fatemeh Javaheri, Majid Namaki-Shoushtari, Parastoo Kamranfar, and Zainalabedin Navabi</i>	
On Generation of 1-Detect TDF Pattern Set with Significantly Increased SDD Coverage	120
<i>Fang Bao, Ke Peng, Krishnendu Chakrabarty, and Mohammad Tehranipoor</i>	

Session A6: Advanced Techniques in Online Testing

Yield-per-Area Optimization for 6T-SRAMs Using an Integrated Approach to Exploit Spares and ECC to Efficiently Combat High Defect and Soft-Error Rates	126
<i>Jae Chul Cha and Sandeep K. Gupta</i>	
A Hybrid Fault Tolerant Architecture for Robustness Improvement of Digital Circuits	136
<i>D.A. Tran, A. Virazel, A. Bosio, L. Dillillo, P. Girard, S. Pravossoudovitch, and H.-J. Wunderlich</i>	
A New Architecture to Cross-Fertilize On-Line and Manufacturing Testing	142
<i>P. Bernardi and M. Sonza Reorda</i>	
Online Test Macro Scheduling and Assignment in MPSoC Design	148
<i>B. Khodabandeloo, S.A. Hoseini, S. Taheri, M.H. Haghbayan, M.R. Babaei, and Z. Navabi</i>	

Session A7: Innovative Techniques in Microprocessor Testing

Distributed Comparison Test Driven Multiprocessor Speed-Tuning: Targeting Performance Gains under Extreme Process Variations	154
<i>Jayaram Natarajan, Joshua Wells, Abhijit Chatterjee, and Adit Singh</i>	
An Online Mechanism to Verify Datapath Execution Using Existing Resources in Chip Multiprocessors	161
<i>Rance Rodrigues and Sandip Kundu</i>	
An Efficient 2-Phase Strategy to Achieve High Branch Coverage	167
<i>Sarvesh Prabhu, Michael S. Hsiao, Saparya Krishnamoorthy, Loganathan Lingappan, Vijay Gangaram, and Jim Grundy</i>	
Soft Error Recovery Technique for Multiprocessor SOPC	175
<i>Uroš Legat, Anton Biasizzo, and Franc Novak</i>	

Session A8: 3D IC Testing

Wrapper Chain Design for Testing TSVs Minimization in Circuit-Partitioned 3D SoC	181
<i>Yuanqing Cheng, Lei Zhang, Yinhe Han, Jun Liu, and Xiaowei Li</i>	
Identification of Defective TSVs in Pre-Bond Testing of 3D ICs	187
<i>Brandon Noia and Krishnendu Chakrabarty</i>	
A Unified Interconnects Testing Scheme for 3D Integrated Circuits	195
<i>Chih-Yun Pai, Ruei-Ting Cu, Bo-Chuan Cheng, Liang-Bi Chen, and Katherine Shu-Min Li</i>	
Cost-Effective TSV Grouping for Yield Improvement of 3D-ICs	201
<i>Yi Zhao, Saqib Khursheed, and Bashir M. Al-Hashimi</i>	

Session A9: Advanced Techniques in Fault Diagnosis II

Improved Fault Diagnosis for Reversible Circuits	207
<i>Hongyan Zhang, Robert Wille, and Rolf Drechsler</i>	
Embedded Test for Highly Accurate Defect Localization	213
<i>Abdullah Mumtaz, Michael E. Imhof, Stefan Holst, and Hans-Joachim Wunderlich</i>	
On Using Design Partitioning to Reduce Diagnosis Memory Footprint	219
<i>Xiaoxin Fan, Huaxing Tang, Sudhakar M. Reddy, Wu-Tung Cheng, and Brady Benware</i>	
Exploring Impact of Faults on Branch Predictors' Power for Diagnosis of Faulty Module	226
<i>Gunjan Bhattacharya, Ilora Maity, Biplab K. Sikdar, and Baisakhi Das</i>	

Session B1: Post-Silicon Debug and Validation

Post-Silicon Timing Validation Method Using Path Delay Measurements	232
<i>Eun Jung Jang, Jaeyong Chung, Anne Gattiker, Sani Nassif, and Jacob A. Abraham</i>	
Backward Reasoning with Formal Properties: A Methodology for Bug Isolation on Simulation Traces	238
<i>Anvesh Komuravelli, Srobona Mitra, Ansuman Banerjee, and Pallab Dasgupta</i>	
Design of a Test Processor for Asynchronous Chip Test	244
<i>Steffen Zeidler, Christoph Wolf, Miloš Krstić, Frank Vater, and Rolf Kraemer</i>	
On Generating Vectors for Accurate Post-Silicon Delay Characterization	251
<i>Prasanjeet Das and Sandeep K. Gupta</i>	

Session B2: Test Compression Techniques

Predicting Scan Compression IP Configurations for Better QoR	261
<i>Jyotirmoy Saikia, Pramod Notiyath, Santosh Kulkarni, Ashok Anbalan, Rajesh Uppuluri, Tammy Fernandes, Parthajit Bhattacharya, and Rohit Kapur</i>	
Low Test Data Volume Low Power At-Speed Delay Tests Using Clock-Gating	267
<i>Elham K. Moghaddam, Janusz Rajske, Sudhakar M. Reddy, and Jakub Janicki</i>	
Test Compression Based on Lossy Image Encoding	273
<i>Hideyuki Ichihara, Yuka Iwamoto, Yuki Yoshikawa, and Tomoo Inoue</i>	
Multiscan-based Test Data Compression Using UBI Dictionary and Bitmask	279
<i>Yang Yu, Gang Xi, and Liyan Qiao</i>	

Session B3: Advanced Techniques in Fault Diagnosis I

Diagnostic Test of Robust Circuits	285
<i>Alejandro Cook, Sybille Hellebrand, Thomas Indlekofer, and Hans-Joachim Wunderlich</i>	
An Accurate Timing-Aware Diagnosis Algorithm for Multiple Small Delay Defects	291
<i>Po-Juei Chen, Wei-Li Hsu, James C.-M. Li, Nan-Hsin Tseng, Kuo-Yin Chen, Wei-pin Changchien, and Charles C.C. Liu</i>	
Diagnosis of Multiple Scan-Chain Faults in the Presence of System Logic Defects	297
<i>Zhen Chen, Sharad Seth, Dong Xiang, and Bhargab B. Bhattacharya</i>	
Diagnosing Multiple Slow Gates for Performance Tuning in the Face of Extreme Process Variations	303
<i>Xi Qian, Adit D. Singh, and Abhijit Chatterjee</i>	

Session B4: Test Quality Improvement Techniques

A Process Monitor Based Speed Binning and Die Matching Algorithm	311
<i>Sreejit Chakravarty</i>	
Optimized Test Error Detection by Probabilistic Retest Recommendation Models	317
<i>Matthias Kirmse, Uwe Petersohn, and Elief Paffrath</i>	
Adaptive Test Framework for Achieving Target Test Quality at Minimal Cost	323
<i>Baris Arslan and Alex Orailoglu</i>	
A Fault Criticality Evaluation Framework of Digital Systems for Error Tolerant Video Applications	329
<i>Yuntan Fang, Huawei Li, and Xiaowei Li</i>	

Session B5: Advanced Memory Test Techniques I

Efficient Use of Unused Spare Columns to Improve Memory Error Correcting Rate	335
<i>Umair Ishaq, Jihun Jung, Jaehoon Song, and Sungju Park</i>	
New Fault Detection Algorithm for Multi-level Cell Flash Memroies	341
<i>Jaewon Cha, Ilwoong Kim, and Sungho Kang</i>	
A New Test Paradigm for Semiconductor Memories in the Nano-Era	347
<i>Said Hamdioui, Venkataraman Krishnaswami, Ijeoma Sandra Irobi, and Zaid Al-Ars</i>	
On Defect Oriented Testing for Hybrid CMOS/Memristor Memory	353
<i>Nor Zaidi Haron, Said Hamdioui, and Nor Zaidi Haron</i>	

Session B6: Advanced Techniques in RF/Mixed Signal Testing

Improving the Accuracy of RF Alternate Test Using Multi-VDD Conditions: Application to Envelope-Based Test of LNAs	359
<i>Manuel J. Barragan, Rafaella Fiorelli, Gildas Leger, Adoración Rueda, and José L. Huertas</i>	
On Replacing an RF Test with an Alternative Measurement: Theory and a Case Study	365
<i>Alexios Spyronasios, Louay Abdallah, Haralampos-G. Stratigopoulos, and Salvador Mir</i>	
Test and Diagnosis of Analog Circuits Using Moment Generating Functions	371
<i>Suraj Sindia, Vishwani D. Agrawal, and Virendra Singh</i>	
Mixed-Signal Fault Equivalence: Search and Evaluation	377
<i>Nuno Guerreiro and Marcelino Santos</i>	

Session B7: Test Automation and Analysis

Efficient BDD-based Fault Simulation in Presence of Unknown Values	383
<i>Michael A. Kochte, Sandip Kundu, Kohei Miyase, Xiaoqing Wen, and Hans-Joachim Wunderlich</i>	
Analysis of Resistive Bridge Defect Delay Behavior in the Presence of Process Variation	389
<i>Shida Zhong, Saqib Khursheed, Bashir M. Al-Hashimi, Sudhakar M. Reddy, and Krishnendu Chakrabarty</i>	
Automation of 3D-DfT Insertion	395
<i>Sergej Deutsch, Vivek Chickermane, Brion Keller, Subhasish Mukherjee, Mario Konijnenburg, Erik Jan Marinissen, and Sandeep K. Goel</i>	

MarciaTesta: An Automatic Generator of Test Programs for Microprocessors'	
Data Caches	401
<i>Stefano Di Carlo, Giulio Gambardella, Marco Indaco, Daniele Rolfo,</i> <i>and Paolo Prinetto</i>	

Session B8: Advanced Memory Test Techniques II

Testing for Parasitic Memory Effect in SRAMs	407
<i>Sandra Irobi, Zaid Al-Ars, Said Hamdioui, and Claude Thibault</i>	
Transient Noise Failures in SRAM Cells: Dynamic Noise Margin Metric	413
<i>Elena I. Vătăjelu, Álvaro Gómez-Pau, Michel Renovell, and Joan Figueras</i>	
Fault Diagnosis in Memory BIST Environment with Non-march Tests	419
<i>Grzegorz Mrugalski, Artur Pogiel, Nilanjan Mukherjee, Janusz Rajski,</i> <i>Jerzy Tyszer, and Pawel Urbanek</i>	
Characterizing Pattern Dependent Delay Effects in DDR Memory Interfaces	425
<i>Atul Gupta, Ajay Kumar, and Manas Chhabra</i>	

Session B9: Innovative DFT Solutions

Breaking the Test Application Time Barriers in Compression: Adaptive Scan-Cyclical (AS-C)	432
<i>Anshuman Chandra, Jyotirmoy Saikia, and Rohit Kapur</i>	
Exploiting Free LUT Entries to Mitigate Soft Errors in SRAM-based FPGAs	438
<i>Keheng Huang, Yu Hu, Xiaowei Li, Gengxin Hua, Hongjin Liu, and Bo Liu</i>	
A Single-Configuration Method for Application-Dependent Testing of SRAM-based FPGA Interconnects	444
<i>Haider A.F. Almurib, T. Nandha Kumar, and Fabrizio Lombardi</i>	
Multi-visit TAMs to Reduce the Post-Bond Test Length of 2.5D-SICs with a Passive Silicon Interposer Base	451
<i>Chun-Chuan Chi, Erik Jan Marinissen, Sandeep Kumar Goel, and Cheng-Wen Wu</i>	

Special Session C1: Memory BIST Advances for Nanoscale Technologies

Physical-Aware Memory BIST Datapath Synthesis: Architecture and Case-Studies on Complex SoCs	457
<i>V.R. Devanathan, Sunil Bhavsar, and Rajat Mehrotra</i>	
Failure Analysis and Test Solutions for Low-Power SRAMs	459
<i>L.B. Zordan, A. Bosio, L. Dillillo, P. Girard, S. Pravossoudovitch, A. Todri,</i> <i>A. Virazel, and N. Badereddine</i>	
A Robust Solution for Embedded Memory Test and Repair	461
<i>K. Darbinyan, G. Harutyunyan, S. Shoukourian, V. Vardanian, and Y. Zorian</i>	

Special Session C2: Advanced Test Topics I

Nand Flash Memory – Product Trends, Technology Overview, and Technical Challenges	463
<i>Manuel A. d'Abreu</i>	
High Level Verification and Its Use at Pos-Silicon Debugging and Patching	464
<i>Masahiro Fujita</i>	

Special Session C3: 3D Integrated Circuits: Design, Test and Yield

3D Specific Systems: Design and CAD	470
<i>Paul D. Franzon, W. Rhett Davis, Thor Thorolfsson, and Samson Melamed</i>	
Testing and Design-for-Testability Techniques for 3D Integrated Circuits	474
<i>Brandon Noia and Krishnendu Chakrabarty</i>	
Yield Improvement and Test Cost Optimization for 3D Stacked ICs	480
<i>Said Hamdioui and Mottaqiallah Taouil</i>	

Special Session C4: Advanced Test Topics II

Integrated Design & Test: Conquering the Conflicting Requirements of Low-Power, Variation-Tolerance and Test Cost	486
<i>Ashish Goel, Swaroop Ghosh, Mesut Meterellioz, Jeff Parkhurst, and Kaushik Roy</i>	

Special Session C5: Robust Systems Research Around the Globe

Dependable VLSI Program in Japan: Program Overview and the Current Status of Dependable VLSI Platform Project	492
<i>Hidetoshi Onodera</i>	
Reliability: A Cross-Disciplinary and Cross-Layer Approach	496
<i>Norbert Wehn</i>	
Underdesigned and Opportunistic Computing	498
<i>Puneet Gupta and Rajesh K. Gupta</i>	

Special Session C6: Power-Aware Testing and Test of Low Power Designs

Power Aware Shift and Capture ATPG Methodology for Low Power Designs	500
<i>Shray Khullar and Swapnil Bahl</i>	
Power-Aware Test Pattern Generation for At-Speed LOS Testing	506
<i>A. Bosio, L. Dilillo, P. Girard, A. Todri, A. Virazel, K. Miyase, and X. Wen</i>	

Power Aware Embedded Test	511
<i>Xijiang Lin, Elham Moghaddam, Nilanjan Mukherjee, Benoit Nadeau-Dostie, Janusz Rajski, and Jerzy Tyszer</i>	

Special Session C7: Post-SI Debug and Validation

Special Session C8: Embedded Tutorial Testability of Cryptographic Hardware and Detection of Hardware Trojans

Testability of Cryptographic Hardware and Detection of Hardware Trojans	517
<i>Debdeep Mukhopadhyay and Rajat Subhra Chakraborty</i>	

Session C9: Board and System Level Testing

Test Scheduling in an IEEE P1687 Environment with Resource and Power Constraints	525
<i>Farrokh Ghani Zadegan, Urban Ingelsson, Golnaz Asani, Gunnar Carlsson, and Erik Larsson</i>	
Automatic SoC Level Test Path Synthesis Based on Partial Functional Models	532
<i>Anton Tsertov, Raimund Ubar, Artur Jutman, and Sergei Devadze</i>	
A Boundary Scan Circuit with Time-to-Digital Converter for Delay Testing	539
<i>Hiroyuki Yotsuyanagi, Hiroyuki Makimoto, and Masaki Hashizume</i>	
Burst-Mode Transmission and Data Recovery for Multi-GHz Optical Packet Switching Network Testing	545
<i>C. Gray, D.C. Keezer, H. Wang, and K. Bergman</i>	
Author Index	552